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**PATENT APPLICATION**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Haruo NISHIDA et al.

Group Art Unit: 2138

Application No.: 10/765,895

Examiner: C. BRITT

Filed: January 29, 2004

Docket No.: 118496

For: TEST CIRCUIT, INTEGRATED CIRCUIT, AND TEST METHOD

**AMENDMENT UNDER 37 C.F.R. §1.111**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In reply to the March 23, 2007 Office Action, please consider the following:

**Amendments to the Claims** as reflected in the listing of claims;

**Amendments to the Drawings** include an attached replacement sheet; and

**Remarks.**